



552 867

(43) International Publication Date
21 October 2004 (21.10.2004)

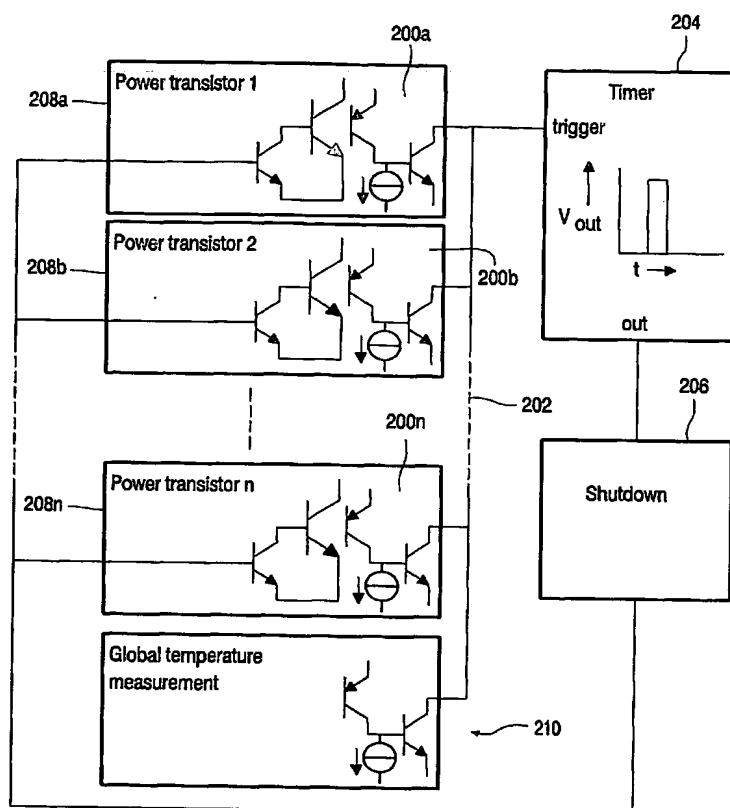
PCT

(10) International Publication Number
WO 2004/091067 A1

- (51) International Patent Classification⁷: **H02H 5/04** Bernardus, H. [NL/NL]; c/o Prof. Holstlaan 6, NL-5656 AA Eindhoven (NL).
- (21) International Application Number: PCT/IB2004/050405 (74) Agent: **DUIJVESTIJN, Adrianus, J.**; Prof. Holstlaan 6, NL-5656 AA Eindhoven (NL).
- (22) International Filing Date: 7 April 2004 (07.04.2004) (81) Designated States (unless otherwise indicated, for every kind of national protection available): AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BW, BY, BZ, CA, CH, CN, CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE, EG, ES, FI, GB, GD, GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, MA, MD, MG, MK, MN, MW, MX, MZ, NA, NI, NO, NZ, OM, PG, PH, PL, PT, RO, RU, SC, SD, SE, SG, SK, SL, SY, TJ, TM, TN, TR, TT, TZ, UA, UG, US, UZ, VC, VN, YU, ZA, ZM, ZW.
- (25) Filing Language: English
- (26) Publication Language: English
- (30) Priority Data: 03100987.1 11 April 2003 (11.04.2003) EP
- (71) Applicant (for all designated States except US): **KONINKLIJKE PHILIPS ELECTRONICS N.V.** [NL/NL]; Groenewoudseweg 1, NL-5621 BA Eindhoven (NL).
- (72) Inventor; and
- (75) Inventor/Applicant (for US only): **KRABBENBORG,**
- (84) Designated States (unless otherwise indicated, for every kind of regional protection available): ARIPO (BW, GH, GM, KE, LS, MW, MZ, SD, SL, SZ, TZ, UG, ZM, ZW), Eurasian (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM), European (AT, BE, BG, CH, CY, CZ, DE, DK, EE, ES, FI, FR,

[Continued on next page]

(54) Title: METHOD AND APPARATUS FOR INTEGRATED CIRCUIT PROTECTION



(57) Abstract: A method and apparatus for protecting an integrated circuit against damage caused by excessive temperatures, the integrated circuit comprising a plurality of power transistors (208a, 208b, 208n). Each of the power transistors (208) is provided with a respective temperature measurement circuit (200a, 200b, 200n). Temperature measurement is based on the temperature dependence of the current through a reverse biased pn junction. All temperature measurement circuits (200) are connected to a pull-down line (202), the trigger input of a timer (204). The timer (204) generates a pulse with a fixed period that is fed to a shutdown circuit (206) that switches off all of the power transistors (208) by pulling base to emitter and disabling all their driver transistors, in the event that the temperature in any one of the power transistors (208) is determined to exceed some predetermined local threshold temperature. A global temperature sensor (210) is also provided to measure temperature of the small signal part of the integrated circuit, and switch off the circuit in the event that this temperature is determined to exceed some predetermined global threshold temperature.

WO 2004/091067 A1



GB, GR, HU, IE, IT, LU, MC, NL, PL, PT, RO, SE, SI, SK, TR), OAPI (BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE, SN, TD, TG).

Declaration under Rule 4.17:

- *as to applicant's entitlement to apply for and be granted a patent (Rule 4.17(ii)) for the following designations AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BW, BY, BZ, CA, CH, CN, CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE, EG, ES, FI, GB, GD, GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, MA, MD, MG, MK, MN, MW, MX, MZ, NA, NI, NO, NZ, OM, PG, PH, PL, PT, RO, RU, SC, SD, SE, SG, SK, SL, SY, TJ, TM, TN, TR, TT, TZ, UA, UG, UZ, VC, VN, YU, ZA, ZM, ZW, ARIPO patent (BW, GH, GM, KE, LS, MW, MZ, SD, SL, SZ, TZ, UG, ZM, ZW), Eurasian patent (AM, AZ, BY,*

KG, KZ, MD, RU, TJ, TM), European patent (AT, BE, BG, CH, CY, CZ, DE, DK, EE, ES, FI, FR, GB, GR, HU, IE, IT, LU, MC, NL, PL, PT, RO, SE, SI, SK, TR), OAPI patent (BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE, SN, TD, TG)

Published:

- *with international search report*
— *before the expiration of the time limit for amending the claims and to be republished in the event of receipt of amendments*

For two-letter codes and other abbreviations, refer to the "Guidance Notes on Codes and Abbreviations" appearing at the beginning of each regular issue of the PCT Gazette.